

Provisional program

7th Workshop " Combined Analysis Using X-rays, electrons and Neutron Scattering "

June 27th – July 1st, 2016, Caen (France)



Monday	Tuesday	Wednesday	Thursday	Friday
9h Welcome Coffee ! (Eric Berthier, Daniel Chateigner)	9h Fluorescence: XRF-GiXRF-TXRF Analysis Including thin structures (Giancarlo Pepponi)	9h Microstructure Analysis size and microstrains defects Size and microstrain distributions (Luca Lutterotti)	9h Residual Stress Analysis Stresses, macrostress Texture and Stresses (Luca Lutterotti)	9h Transmission Electron Microscopy Rietveld of ring patterns (Philippe Boullay)
~10h30 / 11h : coffe break				
10h30 Introduction (Daniel Chateigner) 10h40 Instrumentations Measurements (Henry Pillière)	X-ray reflectivity Analysis Specular reflectivity Fresnel, Parratt Formalisms Roughness (Giancarlo Pepponi)	Quantitative Texture Analysis From pole figures to ODF (Daniel Chateigner)	Combined Analysis from images (Luca Lutterotti)	Rietveld-PDF (Luca Lutterotti)
~12h30 / 14h : Lunch				
Classical Rietveld Analysis Phase analysis (Luca Lutterotti)	Practical session: XRR and XRF on bulk	Practical session Rietveld Texture Analysis	Practical session Stresses of textured films	Practical session TEM examples
~15h30 / 16h : coffe break				
Practical session: Rietveld analysis and Phase Quantification	Practical session: XRD and XRF Combined Analysis	Practical session Combined Phase, Texture and Microstructure	Practical session Stresses-texture from images	Practical session PDF
~18h End of the day				

~19h Dinner

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